

## **Test** Report

Shen Zhen JHC Technology Development Co.,LTD Client Name

B, 3rd Fl, A Block Junxiangda Bldg., No.9

Zhongshanyuan Rd. West, Tongle Village, Nanshan Address

District, Shenzhen City, China, 518052

Fanless In-Vehicle Computer **Product Name** 

2020.03.13 Date

Compliance Laborator Anbotek Shenzhen Anbotek Compliance Laboratory Limited

Code:AB-AR-02-c

Page 1 of 39





# Marking

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   Laboratory Limited.
- 2. Nobody is allowed to photocopy or partly photocopy this test report without written permission of Shenzhen Anbotek Compliance Laboratory Limited.
- 3. The test report is invalid without the signatures of testing engineer, reviewer and approver.
  - 4. The test report is invalid if altered.
  - Objections to the test report must be submitted to Shenzhen Anbotek Compliance Laboratory Limited within 15 days.
  - 6. The test report is valid for the tested samples only.
  - 7. As for test verdict, "—"means "no need for judgment" "N/A" means "not applicable".
  - 8. The test report SZAEK191217003-01-M1 supersedes the test report SZAEK191217003-01 which is withdrawn.

Code:AB-AR-02-c

Page 2 of 39





## **TEST REPORT**

Client Name : Shen Zhen JHC Technology Development Co.,LTD

B, 3rd Fl, A Block Junxiangda Bldg., No.9 Zhongshanyuan Rd. West,

Tongle Village, Nanshan District, Shenzhen City, China, 518052

Report on the submitted sample(s) said to be:

Product Name : Fanless In-Vehicle Computer

2pcs

Basic Model No:SIGM-2650/S002

Model : Serial Model No:SIGM-2650/S001, SIGM-2650/S003, SIGM-2650/S004

SIGM-2650/T001, SIGM-2650/T002, SIGM-2650/T003, SIGM-2650/T004

Trademark : JHCTECH

Description : /

Sample(s)

received quantity

Sample(s)

Testing quantity : 2pcs

Manufacturer : Shen Zhen JHC Technology Development Co.,LTD

Factory : Shen Zhen JHC Technology Development Co.,LTD

Other information : /

Sample(s)

received Date : 2019.12.16

**Testing period** : 2019.12.19 - 2020.1.2

**Report Date** : 2020.03.13

**Test Conclusion:** 

Please refer next page.

Carbs le

Prepared by: Checked by: Approved by:

name: Carlos Ye name: Jimmy Zhou name: Jeff Zhu

Title: Test Engineer Title: Lab Manager Title: Authorized signatory

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Code:AB-AR-02-c

Page 3 of 39





Section No.		Test Item	Test Method	Evaluation
ipotek 1 Anbi	Visual inspection		EN 50155:2017	Pass
mbot 2 N	loo, lu	sulation test	EN 50155:2017	Pass
Ant 3 kotek	Anborek Pe	formance test	EN 50155:2017 and client's requirements	Pass
4 rek	Low temp	perature storage test	EN 50155:2017	o <sup>tell</sup> Pass M
5 Anbo	Low temp	perature start-up test	EN 50155:2017	Pass
potek Anbo	Dry heat test		EN 50155:2017 and client's requirements	Pass
Zek Zek	Cyclic	c damp heat test	EN 50155:2017	Pass
Aupotek V	Aupotek Au	Functional random vibration test	hotek Anbotek Anbote	otek Anbor
8 Anbore	Vibration and shock test	Simulated long life test	EN 50155:2017	Pass
inbotek Ant	potek Anbore	Shock test	Anbotek Anbotek	
Anbore 9 otek	Anbotek Pol	ver supply test	EN 50155:2017	Pass



Jek Jos	ection	k potek	Anbotek Anb	Aupo, A
Test Method	EN 50155:2017	tek vupotek	Anbotek Anbotek Anbotek	Anbore
Test Condition	Visual inspectio	n of the sample a	at 25 °C ± 10°C	ek Augo
Test Requirement	The appearance	e of the sample is	s normal without damage.	anbotek Anbo
	Sample No.	Auporgek	Test Result	Conclusion
Test Result	SZAEK19121 7003-1-2-1	The appeara	nce of the sample was normal without damage.	Pass
	Anbotok  2 1 2 3 4 5 6 7  2 1 2 3 4 5 6 7			
	Sam	nple as received	Sample as rec	eived
Photosinbote Anbotek		nple as received	Sample as rec	Anbotek Anbotek Anbotek Anbotek Anbotek Anbotek

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Code:AB-AR-02-c

Page 5 of 39



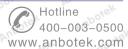


2. Insulation to	est pr	Pur Vur	botek Anbo	ter. Vupe	anboiek A	Upo, b
Test Method	EN 5015	5:2017	and abotek Ar	potek Anbo	tek Anbotek	Aupore.
est Condition	2. Voltag	e withstand te		5) 50HZ, 1 minute not be powered o	potek Anbotek	Anbotek Anbotek
	Equipme	nt Name	Equipment No.	Equipment	model i i	oment Cal ity period
Test Equipment	Insula Resis Tes	tance	SE-2167	TOS72	200	20.4.2
Anbotek Anbotek	127.	tester	SE-2174	TOS5	01 20	20.4.2
Test Requirement	2. Neither test.With	er disruptive o stand voltage	discharge nor flatest current ≤10 test, the equipm	ashover shall occ mA. ent shall work as	cur during the volta	n its specifie
	No.	Yek Vupo,	iek Anbote Te	est Result	Anbotek Anbor	Conclusion
	atek Anb	Insulation re	esistance (MΩ)	Voltage withstand test	Functional check	nbotek
Test Result	SZAEK 191217 003-1-2	Before voltage withstand test	After voltage withstand test	Neither disruptive discharge nor flashover	The equipment could work as	Anborek Anborek Pass
	otek A	>5000	>5000	occurred. Withstand voltage test	intended and within its specified limits .	nbotek Anbotek
	hbotek	Anbotek Anbotek	Anbotek A	current <10mA.	tek Anbotek	Anborek
Anbotek Anbotek Anbotek Anbotek			.,,0,	N. Co.		
	10			one <sup>y</sup>	4 1000	
Photos	Anbotok Anbotok Anbotok Anbotok Anbotok	2 3 4 5 6 7 8 9 10 11 12 13	14 15 16 17 18 19 <mark>20</mark> 21 22 23 24 26 26 27 28	7.C		

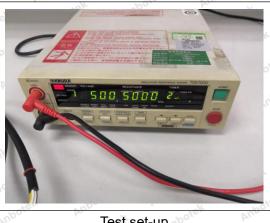
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Code:AB-AR-02-c

Page 6 of 39









Photos

Test set-up
Insulation resistance test

Test Set-up
Voltage withstand test



Test Set-up
Voltage withstand test

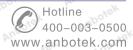
1



3. Performance	e test	Anbotek An
Test Method	According to EN 50155:2017 and client's requirements	Aupoter
Test Condition	The equipment can operate normally and The indicators of each changafter the sample is powered on.	nel are norma
Test Requirement	The equipment can operate normally and The indicators of each channafter the sample is powered on.	nel are norma
-botek Anbot	Sample No. Test Result	Conclusion
Test Result	SZAEK191 217003-1-2- 1 The equipment can operate normally and The indicators of each channel are normal after the sample is powered on.	of Pass
Anborek Anborek Anborek Anborek Anborek Anborek Anborek Anborek Anborek	(A)	
poiek And	Before test Test set-up	Anbote.

Code:AB-AR-02-c

Page 8 of 39





l. Low temper	ature storage test	Aur			abotek		
Test Method	EN 50155:2017	ik abotek	Anborek	Auporek	Anbotek	Anbor	. e.K
est Condition	The equipment is After recovery, a	164	The state of the s		D/1.		
ek Test noorek	Equipment Name	e Equipmer	nt No. E	quipment mo	del 🔀	quipment alidity per	
Equipment	Temperature & humidity chambe	sE-33	O1 nbore	ZJ-HWS1000	O'upo ek	2020.8.2	2
Test Requirement	After recovery, the 1.The apparatus 2.No degradation	shall continue to	o operate as ir	ntended durir	g and after		
k Wpotek	Sample No.	hotek An	Test Re	esult	abotek P	Conc	lusic
Test Result	SZAEK19121 a	After recovery, and within its spe normally and Th afte	ecified limits.	Γhe equipme of each chann	nt can opera el are norm	ite Moore	ass
	Anbotek  Anbotek	7 10 11 12 13 14 15 16 17 18 19 20 21 22 23	24 25 20 27 28 29 30 313		WI THE STATE OF TH		
	otek Anbotek B	efore test	Anbotek	Anborek	Test set-up		
Photos	○ 程式运行	VUpo	o ek		Anbotek Anbotek	ak Anbot	
	温度 -40.00	-40.1	1 c				
			20				
	0.0	运行总时间	%RH				
	0.0 程式组别 2	运行总时间(	%RH		Anbotek Anbotek		

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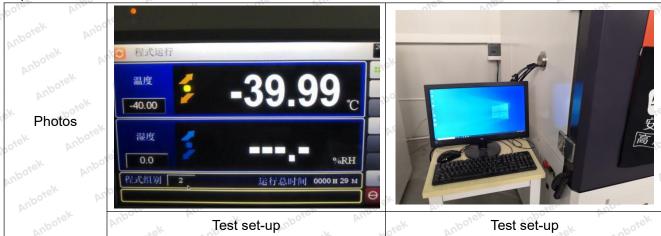
Page 9 of 39





5. Low temper	ature start-up test	in otek anbotek	Aupo, ek -po	tek Anbore
Test Method	EN 50155:2017	Anborre Anborre	k Aupole Au	botek Anbotek
Test Condition	chamber at-40 °C, for At the end of this per carried out, keeping	aced without any volta or 2 h to achieve stab riod the equipment sh the equipment at the	all be switched on and a	a performance check i
Test	Equipment Name	Equipment No.	Equipment model	Equipment Cal validity period
Equipment	Temperature & humidity chamber	SE-3301	ZJ-HWS1000C	2020.8.22
Test Requirement	1. The apparatus sh	nall continue to operat	hall work as intended. se as intended during ar s of function is allowed.	nd after the test.
Anborek An	Sample No.	Anborek Test 1	Result	Conclusion
Test Result	191217 within its	specified limits. The e	nt could work as intende equipment can operate of channel are normal afte powered on.	normally Pass
Anbotek Ant				Our. Vin
Photos potek	Anberek 2 1 2 3 4 5 6 7 8 9 10 111	12 13 14 15 16 17 18 19 <mark>20</mark> 21 22 23 24 25 26 27 26 29 30 31		





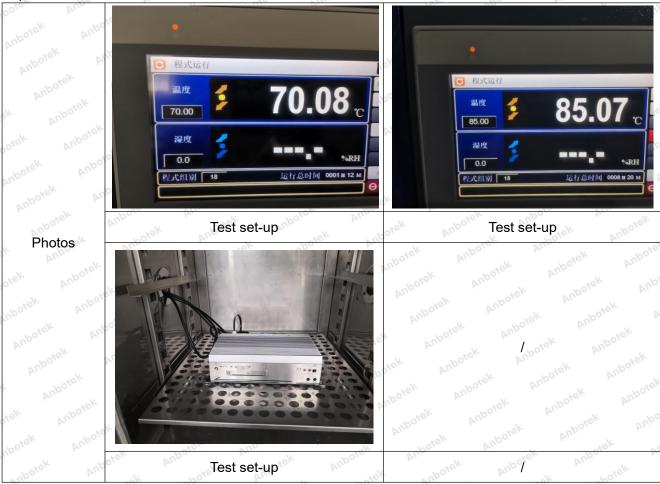
Code:AB-AR-02-c

Page 11 of 39



6. Dry heat tes	tek Anbore					
Test Method	According to E	N 50155:2017 a	nd client's requirem	ents	hotek Ar	boser
Test Condition	the equipment Rise the tempe checks carried	shall be switche erature to 85°C a t is then allowed	n temperature to 70 d on operational che it 1 °C/min, left for 1 to cool to ambient to	ecks carried. 0 min with con	tinuous opera	
Test	Equipment Na	ame Equipm	ent No. Equip	ment model	Equipme validity	
Equipment	Temperature humidity cham	~0, SH7.	3301 ZJ-H	IWS1000C	2020.	8.22 <sub>Anbot</sub>
Test Requirement	1. The appara	itus shall continu	quipment shall work e to operate as inte nce or loss of functi	nded during ar	nd after the te	st <sub>k</sub>
Andhorek	Sample No.	otek vupote	Test Result	Yun Potek	Aupotek C	onclusior
Test Result	SZAEK1912 17003-1-2-1	within its spe	the equipment could cified limits. The equal The indicators of each ter the sample is po	uipment can o <sub>l</sub> ch channel are	perate	Pass
Photos	Androis 1 2 3 4 5 6	7 8 9 10 11 12 13 14 15 16 17 18 19 20 21	22 22 24 25 26 27 28 29 30 313			
40.	A Control of the Cont	The same of the sa	The second secon	Mar.		





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Code:AB-AR-02-c

Page 13 of 39



7. Cyclic damp	o heat test	Abotek I	Anbore. And	otek Anbotek	Aupo.
Test Method	EN 50155:2007				
Test Condition	The equipment under Temperatures: 55°C Number of cycles:2 Test time:2×24h Intermediate measure temperature during	and 25℃ rements:an ope the beginning c	erational check sh of the 2nd cycle.	Anbotek Anbotek	
Anboatek	Insulation resistance Withstand voltage to	- OK	200	upo otek	
Anbotek	Equipment Name	Equipment	Aupor	nent model	Equipment Cal validity period
or <sup>ok</sup> Test <sub>An</sub> bot	Temperature & humidity chamber	SE-3301	ZJ-HV	VS1000C	2020.8.22
Equipment	Insulation Resistance Tester	SE-2167	, Anboard TO	S7200	2020.4.2
	Withstand voltage tester	SE-2174	ТО	S5101	2020.4.2
Test Requirement	cycles)shall be within 2.Before and after equipment shall wor 1) The apparatus so 2) No degradation of	the test(initia k as intendeds hall continue to	I and final volta specified limits operate as inten	ige withstand	and insulation), the
Anbotek	Sample	Item	Initial	Final	Conclusio
	ak hore	lation tance	>5000 MΩ	>5000 M	Ω Anbotek
Test Result	SZAEK 191217 003-1-2 -1	d voltage fla	either disruptive discharge nor shover occurred. /ithstand voltage test current <10mA.	Neither disru discharge flashover occ Withstand vo test curre <10mA.	nor urred. oltage nt
	within its	specified limits	uipment could wo s. The equipment f each channel ar	can operate no	rmally

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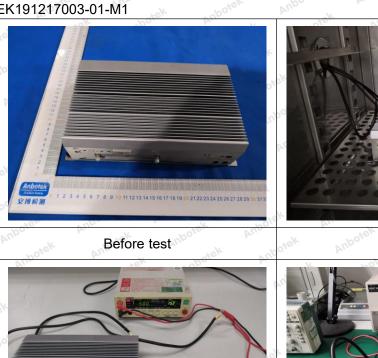
Page 14 of 39





Photos

## Report No.:SZAEK191217003-01-M1



After test

After test

Test set-up



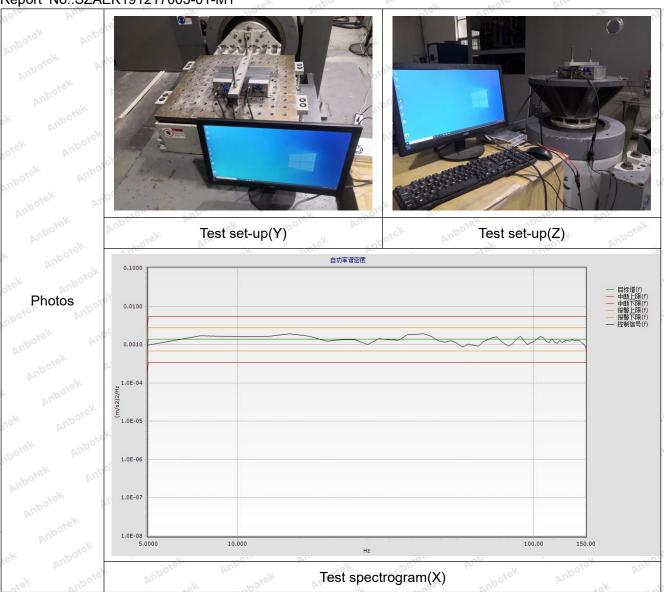
	nd shock test				
8.1 Functional	random vibration te	est aborek Anbore	k Aupore Au	boiek	Aupoter
Test Method	EN 50155:2017	anbotek Ant	oren Andorek	Aupotek	Aupo
r anbotek	Anbore And	Direction	RMS(m/s²)	Aup Ere	equency
	Anboro And	Vertical	And hotel.01 Anborek	Anbo	otek or
	Class B	Horizontal	0.45	5Hz	~ 150Hz
Test Condition	boten Anbotek	Longitudinal	0.70	poter.	
Anbotek	Test time	rek Aupotek V	10 min per direction.	Aupotek	Aupotek Brandotek
	Test mode	upotek Aupotek	power on		
po <sup>tek</sup> Anbot	Equipment Name	Equipment No.	Equipment model	101	pment Cal lity period
Equipment	Vibration tester	SE-1199	DC-2200-26	20	19.12.25
Anbotek	1.No damage shall	occur during the test	to tek Anbotek	Aupo	Sk spoke
Test Requirement	2.During the test, th	70, D.	te as intended during ar	nd after th	e test.
	2.During the test, th	ne equipment shall wor shall continue to operat of performance or loss	te as intended during ar	nd after th	e test.  Conclusion
	2.During the test, th  1) The apparatus s  2) No degradation  Sample No.  SZAEK19121 1. N	ne equipment shall wor shall continue to operat of performance or loss Tes No damage occurred de	te as intended during ar s of function is allowed. st Result	otek Imbotek	Aupotek L
Requirement	2.During the test, th  1) The apparatus s  2) No degradation  Sample No.  SZAEK19121 1. N  7003-1-2-2 2. E	ne equipment shall wor shall continue to operat of performance or loss Tes No damage occurred de	te as intended during ar s of function is allowed. st Result uring the test.	otek Imbotek	Conclusion

Code:AB-AR-02-c

Page 16 of 39







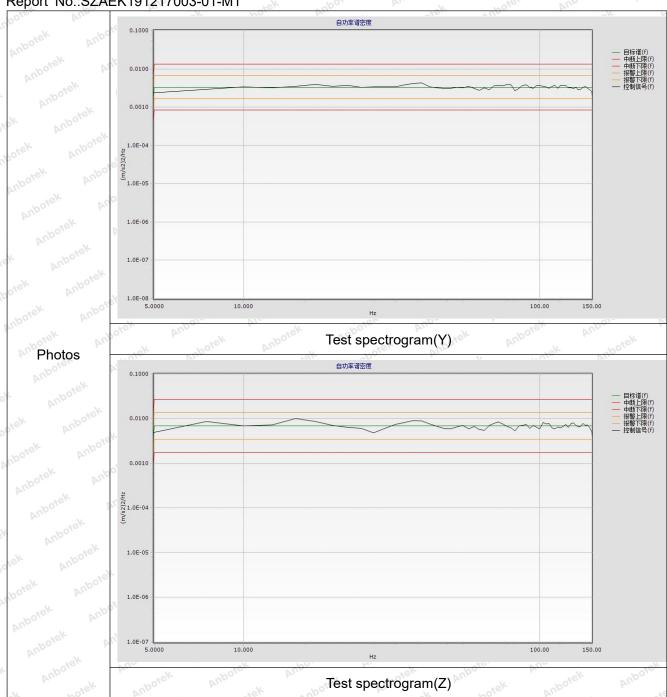
Code:AB-AR-02-c

Page 17 of 39









**Shenzhen Anbotek Compliance Laboratory Limited** 

Code:AB-AR-02-c

Page 18 of 39

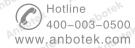




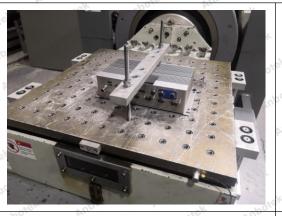
8.2 Simulated	long life test			
Test Method	EN 50155:2017	Anbotek Anbote	Sk Aupone Will	nbotek Anbotek
Anbotek	Anborek Anb	Direction	RMS(m/s²)	Frequency
	Anborek 1k	Vertical	5.72	Anbotek Anbo
	Class B	Horizontal	2.55	5Hz ~ 150Hz
Test Condition	lek Wupo,	Longitudinal	3.96	lek Aupo, diek
	Test time	ntek Anbortek Anborte	5 hours per direction.	hotek Anbotek
Anbotek Anbotek	Test mode	hbore Anborek Anborek	power off	Anbotek Anbote
rek Test	Equipment Na	me Equipment No.	Equipment model	Equipment Cal validity period
Equipment	Vibration test	er SE-1199	DC-2200-26	2019.12.25
Requirement	D1.	tus shall continue to opera tion of performance or loss		test. Anbotek Anbo
ootek Aupor	Sample No.	Anbotek Anbo Te	st Result	Conclusion
Test Result	SZAEK19121 7003-1-2-2	No damage occurred d     During the test, the equ	·	Pass
Anborek Anborek Anborek Anborek Anborek Anborek Anborek Anborek	AADOUAL VIG ROW 1 2 3 4 5 6	7 8 9 10 11 12 13 14 15 16 17 18 19 10 21 22 23 24 25 24 27 28 29 31 32 33 34 31 3		
	ok hotek	Before test	Wholek Tupore	set-up(X)

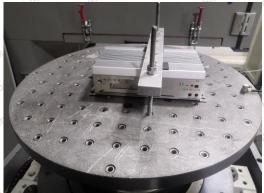
Code:AB-AR-02-c

Page 19 of 39





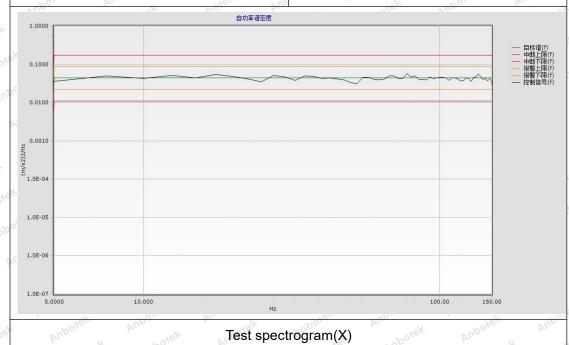




Test set-up(Y)

Test set-up(Z)

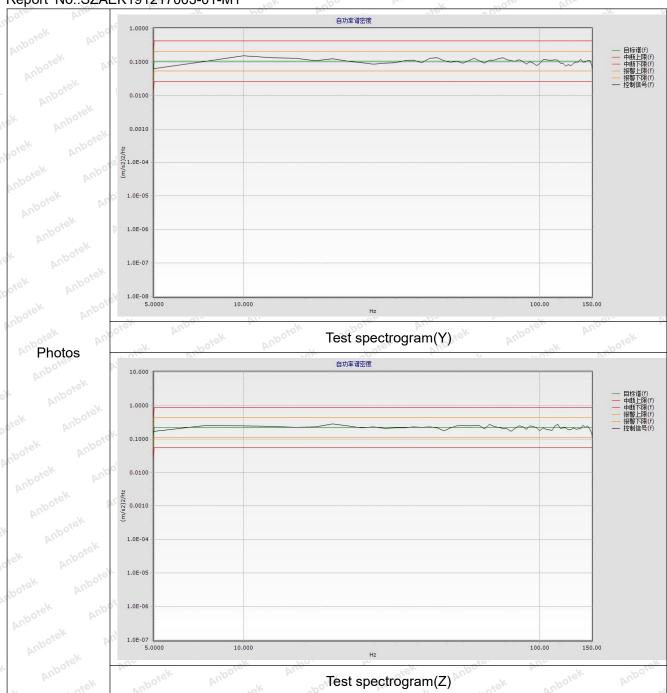




Code:AB-AR-02-c

Page 20 of 39





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Code:AB-AR-02-c

Page 21 of 39





8.3. Shock tes	tek Anbore			
Test Method	EN 50155:2017	Anbotek Anbot	ek Aupon An	hotek Anboten
Aupotek	Classification	n Direction	Acceleration(m/s²)	Pulse width(ms)
	Vupots, b	Vertical	notek 30 Anbotek	Anborn 30
Test Condition	1 Class B	Horizontal	Ananbotek30 Anbotek	30
	Anso 2	Longitudinal	Anboo	30
	Test time	3 times	in each direction, 18 tim	es in total
Test	Equipment Na	me Equipment No.	Equipment model	Equipment Cal validity period
Equipment	Vibration test	er SE-1199	DC-2200-26	2019.12.25
Requirement	27.	tus shall continue to opera tion of performance or loss Te		test. Conclusio
Test Result	SZAEK19121 7003-1-2-2	No damage occurred d     after the test, the equip	uring the test.	Pass
	1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1	100	latava	6
Anbotek Anbotek otek Photos otek Anbotek Anbotek	Anbotak  Vito 6 M	7		8

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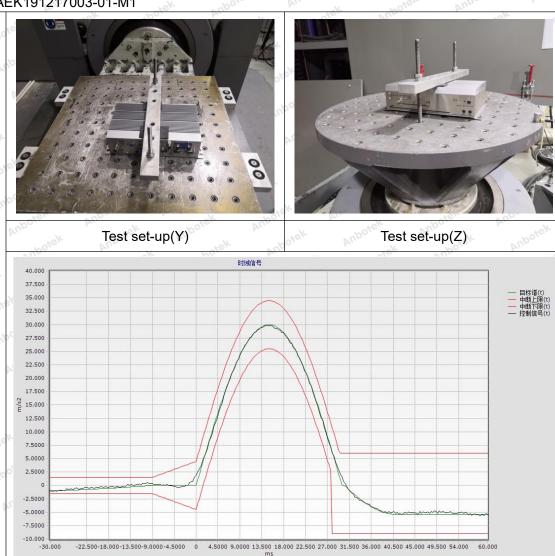
Page 22 of 39





**Photos** 

## Report No.:SZAEK191217003-01-M1



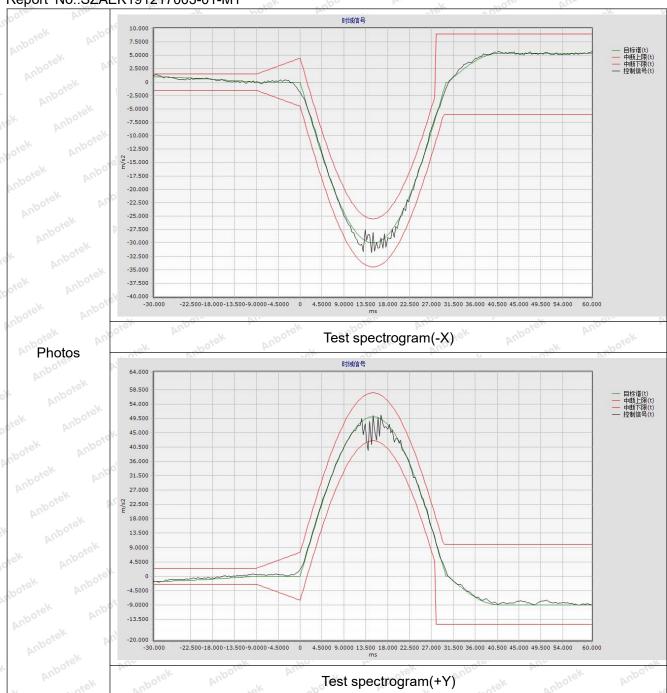
Test spectrogram(+X)

Code:AB-AR-02-c

Page 23 of 39







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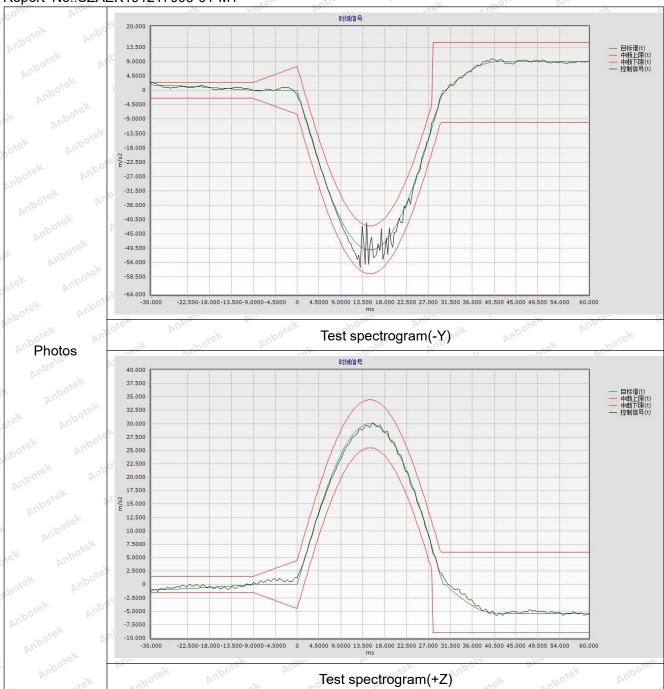
Code:AB-AR-02-c

Page 24 of 39









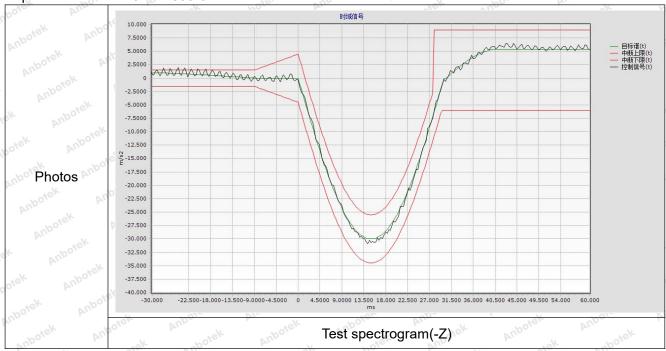
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Code:AB-AR-02-c

Page 25 of 39







Shenzhen Anbotek Compliance Laboratory Limited

Code:AB-AR-02-c

Page 26 of 39

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400-003-0500 www.anbotek.com

Hotline



## 9 Power supply test

#### 9.1 Test requirements

Test standard: EN 50155:2017

Sample NO.: SZAEK191217003-1-2-2

Sample status: Bare machine, power on

Test conditions:

a) EMC and RF testing according to national / international standards

b) Input Power: 110V DC

c) The test shall be carried out in accordance with the provisions of the standards en 50155:2017 13.4.3.2, en 50155 13.4.3.3, en 50155 13.4.3.4 and en 50155 13.4.3.5.

#### 9.2 Summary of Test results

Test items	Standard	Criteria Requirement	Result	Conclusion
Supply variations(Figure 6)	EN 50155 13.4.3.2	Criterion A	Anbote	Pass
Supply variations(Figure 7)	EN 50155 13.4.3.2	Criterion B	A	orek Pass noon
Temporary supply dips	EN 50155 13.4.3.3	Criterion A	A	Pass
Interruptions of voltage supply	EN 50155 13.4.3.4	Criterion A	boyen A	Pass
Supply change-over	EN 50155 13.4.3.5	Criterion A	A	Pass



## 9.3 Supply variations

## 9.3.1 Test Summary

Test Room : Shielding room1

Power Source (Un) : DC 110V

Standards : EN 50155:2017 (13.4.3.2)

EUT configuration : normal

## 9.3.2 Block diagram of test setup



#### 9.3.3 Measurement method

Tests shall be performed to prove correct functioning at nominal supply voltage and at the specified upper and lower limits.

DC power supply range:

Tests shall be performed to prove correct functioning for the voltage range.

DC power supply fluctuation:

The rise/fall waveforms of the diagrams are purely indicative.

Temporary supply overvoltages shall be assumed to be generated with respect to the control system voltage supply return potential and to be present only as an increase to the level of the control system voltage, which shall be assumed to be present before and after the application of the overvoltage. Overvoltage of opposite polarity to the control of the system voltage supply need not be considered.

Overvoltage exceeding in duration or amplitude the specified voltage fluctuation shall be assumed to

occur only in the case of a failure in the control system voltage supply.

Temporary supply overvoltages up to 1,4 Un lasting no more than 0,1 s shall not cause deviation of function (**performance criterion A**).

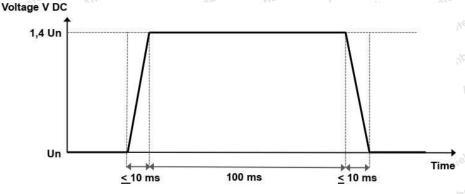


Figure 6 — Temporary supply overvoltages (a)

Code:AB-AR-02-c

Page 28 of 39





For temporary supply overvoltages up to 1,4 Un lasting no more than 1 s the equipment shall fulfil **performance criterion B**.

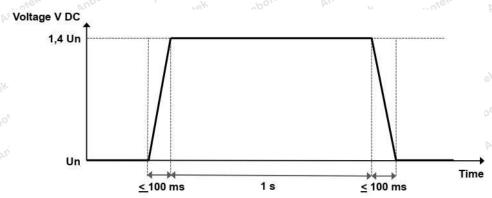


Figure 7 — Temporary supply overvoltages (b)

#### 9.3.4 Result

**PASS** 

EUT : Fanless In-Vehicle Computer

Power Source (Un) : DC 110V

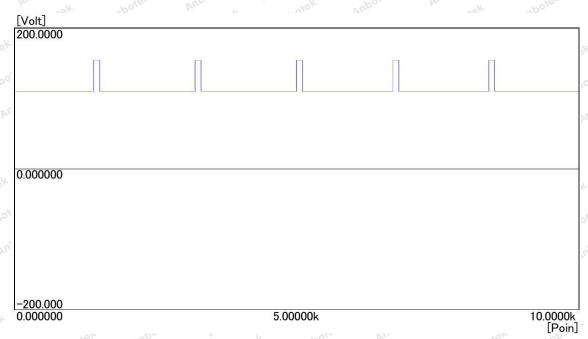
Test Level : 154V (1.4 Un)

sequence number : 10

interval time : 30s

Dwell time : 100ms

Result : Criteria A



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Code:AB-AR-02-c

Page 29 of 39





EUT Fanless In-Vehicle Computer

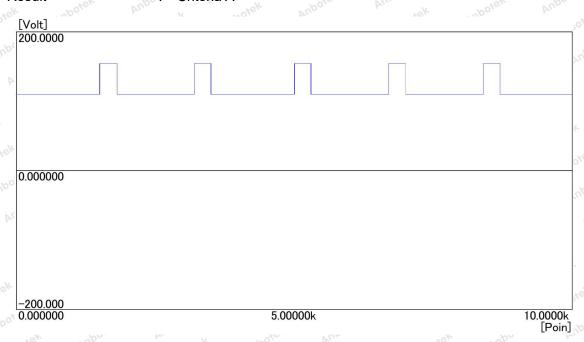
1s Anb

Power Source (Un) : **DC 110V** 

Test Level 154V (1.4 Un)

sequence number 10 interval time 30s Dwell time

Result Criteria A



Code:AB-AR-02-c

Page 30 of 39





## 9.4 Temporary supply dips

## 9.4.1 Test Summary

Test Room : Shielding room1

Power Source (Un) : DC 110V

Standards : EN 50155:2017 (13.4.3.3)

EUT configuration : normal

## 9.4.2 Block diagram of test setup



#### 9.4.3 Measurement method

Voltage dips are mainly caused by faults in the DC distribution system, or by sudden large changes of load (low impedance condition).

Temporary supply dips down to 0,6 Un not exceeding 0,1 s shall not cause deviation of function (performance criterion A).

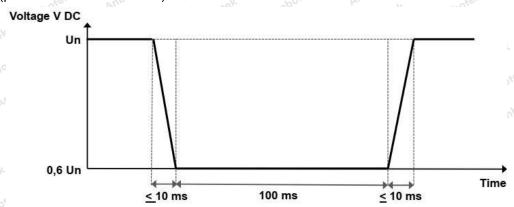


Figure 8 — Temporary supply dips



9.4.4 Result PASS

EUT : Fanless In-Vehicle Computer

Power Source (Un) : DC 110V

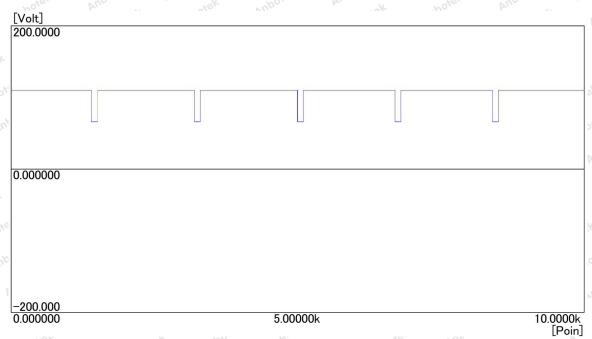
Test Level : 66V (0.6 Un)

Sequence number : 10

Interval time : 30s

Dwell time : 0.1s

Result : Criteria A



Code:AB-AR-02-c

Page 32 of 39





Report No.:SZAEK191217003-01-M1 9.5 Interruptions of voltage supply

#### 9.5.1 Test Summary

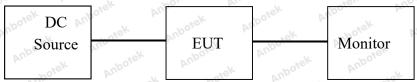
Test Room Shielding room1

Power Source (Un) DC 110V

Standards EN 50155:2017 (13.4.3.4)

**EUT** configuration normal

## 9.5.2 Block diagram of test setup



#### 9.5.3 Measurement method

During a short interruption, the DC distribution system presents a "low impedance" (short circuit) condition due to the clearing of an overload or fault condition on the supply bus. This condition can cause reverse current (negative peak inrush current) from the load. Regarding interruptions on supply voltage, there are three classes of equipment:

Table 13 — Interruptions of voltage supply classes

Class	Requirements	Duration of the interruption time Tint (See Figure 9)	
S1	No performance criterion is requested but the equipment shall continue to operate as specified after the voltage interruption.	NOTE As defined in 5.1.1.4, this test is not required.	
S2	The equipment shall behave according performance criterion A.	10 ms	
S3	The equipment shall behave according performance criterion A.	20 ms	

For voltage interruption longer than specified within the class, equipment shall behave at minimum according performance criterion C.

Tests shall be carried out at nominal voltage.

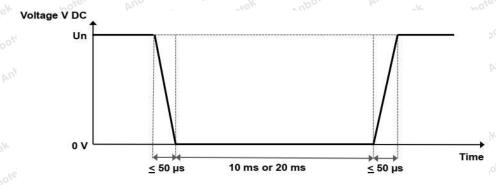


Figure 9 — Interruption of supply voltage

Code:AB-AR-02-c

Page 33 of 39





9.5.4 Result **PASS** 

> EUT Fanless In-Vehicle Computer

Power Source (Un) **DC 110V** 

0V Test Level

10<sup>P</sup> Sequence number

Interval time 60s

10ms (class S2) Dwell time

Result Criteria A

[Volt]				
[Volt]  200.0000				
0.000000	JI.			
-200.000 0.000000		F 00/	2001	10,0000
0.000000		5.000	JUUK	10.0000k [Poin]

Shenzhen Anbotek Compliance Laboratory Limited

Code:AB-AR-02-c

Page 34 of 39





## 9.6 Supply change-over

#### 9.6.1 Test Summary

Test Room : Shielding room1

Power Source (Un) : DC 110V

Standards : EN 50155:2017 (13.4.3.5)

EUT configuration : normal

## 9.6.2 Block diagram of test setup



#### 9.6.3 Measurement method

In the case of equipment supplied with power alternatively from an accumulator battery and a DC stabilized source, the DC distribution system presents a "high impedance" condition due to switching from one source to another.

The equipment shall operate satisfactorily under the conditions stated in Subclauses 5.1.1, 5.1.1.2, 5.1.1.6 and 5.1.3.

- -Class C1: at 0,6 Un during 100 ms (without interruptions). Performance criterion A;
- —Class C2: during a supply break of 30 ms starting at Un Performance criterion B.

The supply break is an open circuit and not a short circuit "( high impedance" condition). Unless otherwise specified, the requirements of class C1 apply to power supply only.

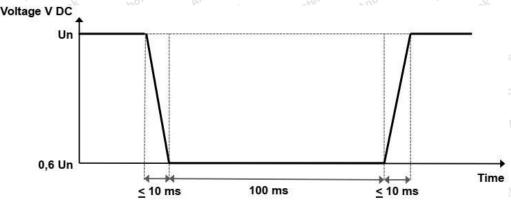


Figure 10 — Supply change-over Class C1

Code:AB-AR-02-c

Page 35 of 39



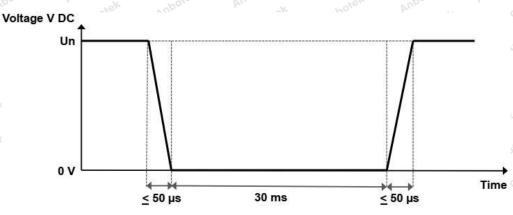


Figure 11 — Supply change-over Class C2

#### 9.6.4 Result

**PASS** 

EUT : Fanless In-Vehicle Computer

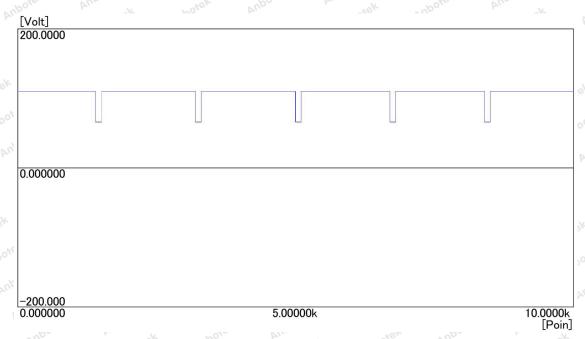
Power Source (Un) : DC 110V

Test Level : 66V (0.6 Un)

Sequence number : 10
Interval time : 30s

Dwell time : 100ms (class C1)

Result : Criteria A



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Code:AB-AR-02-c

Page 36 of 39





## 9.7 Test equipment

Equipment Name	Equipment No.	Equipment model	Equipment Cal validity period
Power Source	SE-5001	KP3000GS	2020.04.22
Test software	SE-5002	KP-G (V1.0.0)	2020.04.22

## 9.8 Test Uncertainty

botek Anb Test Anbotek	Confidence Level	CISPR Uncertainty	Our Uncertainty
Radiated emission (3m) 30-1000MHz	95%	5.2dB	4.3dB
Conducted Emission(Mains) 0.15- 30MHz	95%	3.6dB Anbot	3.3dB

## 9.9Test photos



Sample photos

Code:AB-AR-02-c

Page 37 of 39







Sample photos



Sample photos





Test setup photos

\*\*\*End of Report\*\*\*